



ETW '02

7th IEEE European Test Workshop

GrecoTel Corfu Imperial Hotel, Corfu, Greece

May 26 – 29, 2002



Call for Papers

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The IEEE European Test Workshop is a well-recognized forum for presenting and discussing trends, emerging results, practical applications, and hot topics in the area of electronic-based circuit and system testing. The seventh workshop will take place in 2002 at Corfu Island, the "Emerald Island" of Greece, known for its elegant architecture and its mountainous skyline plunging into the bluest of blue waters.

ETW'02 is sponsored by the IEEE Computer Society - Test Technology Technical Council (TTTC) and co-organized by the University of Athens and the University of Piraeus.

We cordially invite you to participate and submit your contribution to ETW'02, which includes (but is not limited to) the following topics:

- Analog, Mixed-Signal and RF Test
- ATE Hardware and Software
- ATPG and High Level TPG
- Debug and Diagnosis
- Defect/Fault Tolerance and Reliability
- Design Verification/Validation
- Emerging Testability Standards
- Failure Analysis, Defect and Fault Modelling
- Fault Simulation
- FPGA and Embedded PGA Test
- High Level DfT
- IDDX Test
- Low Cost Testers
- Memory and Processor Test
- MEMS Testing
- On-Line and Off-Line BIST
- Scan-based Techniques and Boundary Scan
- Self-Repair Methodologies
- Signal Integrity Test
- Systems Test
- Test of Embedded Cores and Systems-on-Chip
- Test of MCMs and Boards
- Test Resource Partitioning and Embedded Test
- Test Synthesis and Synthesis for Testability
- Thermal Testing
- Yield Analysis and Yield Enhancement

Submissions: For the *Research Track*, the Program Committee invites original submissions of at least 1,000 and at most 5,000 words focusing on new concepts and methodologies; full paper submissions are preferred. For the *Application Track*, extended abstract or full paper submissions are invited focusing on case studies and reports on industrial and/or academic experiences, practices and developments.

Electronic submission in Postscript or PDF via the workshop web page, which also informs about the *review criteria* for both Tracks, is strongly encouraged. Please identify a contact author with complete information (mailing address, phone number, fax number and e-mail address).

Proceedings: On site, ETW'02 will deliver handouts of the accepted contributions whose authors wish to provide the corresponding materials. After the workshop, *formal proceedings* of selected papers will be published by the IEEE Computer Society. The Program Committee will select the contributions to be included in the formal proceedings based on the review results and the quality of the papers included in the handouts. The best contributions will appear in a *special issue* of the *Journal of Electronic Testing: Theory and Applications* (JETTA), published by Kluwer.

Deadlines and Key Dates:

- Submission of full papers or extended abstracts: **February 1, 2002**
- Notification of acceptance: **March 25, 2002**

IEEE TTTC Test Technology Educational Program (TTEP) 2002

TTEP 2002 tutorials will be offered during May 26 on emerging test technology topics. Tutorial proposals should be submitted according to the guidelines at <http://computer.org/tab/ttcc/teg/ttep>

Further Information:

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Please visit the ETW 2002 web page at: <http://www.unipi.gr/etw02>